

Notice of References Cited	Application/Control No. 10/690,708		Applicant(s)/Patent Under Reexamination VICKER ET AL.	
	Examiner Golam M. M. Shameem, Ph.D.		Art Unit 1626	Page 1 of 1

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*	B	US-6,579,881	06-2003	Kitazawa et al.	514/254.02
*	C	US-6,638,965	10-2003	Walter et al.	514/418
*	D	US-6,316,474	11-2001	McCauley et al.	514/338
*	E	US-5,585,395	12-1996	Lunkenheimer et al.	514/395
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NON-PATENT DOCUMENTS

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	U	Yoshino et al (1995): STN International HCAPLUS database, Columbus (OH), accession number: 1995:713785.
	V	Kitazawa et al (1998): STN International HCAPLUS database, Columbus (OH), accession number: 1998:682229.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.